

## FUSE CIRCUIT FOR SEMICONDUCTOR INTEGRATED CIRCUIT

### Abstract of the Disclosure

5           In a fuse circuit including programmable fuses in a semiconductor  
integrated circuit, the fuses store specific information related to the  
semiconductor integrated circuit, such as redundancy information, wafer lot  
number, die lot number, and die position on the wafer, etc. While a  
conventional semiconductor integrated circuit utilizes a single fuse for storing  
10 one bit of specific information, the fuse circuit in the present invention utilizes  
a plurality of fuses for storing identical bit information. Consequently, in the  
case where a fuse has not been cut out correctly, the fuse circuit of the present  
invention can reduce programming defects, whereby defect generation rates  
are remarkably decreased.

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